

Notice of References Cited	Application/Control No. 10/726,382		Applicant(s)/Patent Under Reexamination YEH ET AL.	
	Examiner James A. Dudek		Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0218706 A1	11-2003	Takizawa et al.	349/110
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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